



Upcoming Events

Semicon West

Booth # 5873 North Hall

Moscone Center
San Francisco, CA
July 14-16, 2009

Intersolar

Booth # 8559

Moscone Center
San Francisco, CA
July 14-16, 2009

One Day Analytical Symposium

With PerkinElmer

San Francisco Marriott
Jul 15, 2009

More information [here](#)

Chromatography Lunch and Learn Seminar

With Dionex Corporation

Fremont, CA
Jul 24, 2009

More information [here](#)

www.balazs.com

Meet us at Semicon West and Intersolar

Visit our booths for in-depth information of our capabilities, to discuss a contamination test plan or to schedule an in-house technical training.

SEMICON®
West2009

Evaluation of Impurities in High-K and Low-K Thin Films Produced from Advanced Precursor Materials

New materials are rapidly coming into use in semiconductor manufacturing to accommodate shrinking feature size at the 45 nm node and beyond. Metal oxides and oxynitrides based on hafnium, zirconium, and others offer an attractive high-k (dielectric constant) replacement for silicon dioxide in transistor gates and other sensitive structures. These oxide films are typically formed by CVD (chemical vapor deposition) using a volatile precursor compound to deliver the desired metal in the vapor phase to the wafer surface. Subsequent reactions on the surface result in the desired oxide film...



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New Contamination Monitoring Applications Available with Automated VPD ICP-MS

The importance of metal contamination in semiconductor processing and the ultimate yield effects has long been understood in the fab. One particular method used to measure metallic contamination is Vapor Phase Decomposition (VPD) in combination with Inductively Coupled Plasma Mass Spectrometry (ICP-MS). With this technique low detection limits (10^7 atoms/cm²) can be obtained for metals across the periodic table. A new application available now at Balazs is the application of an automated VPD system that automates the VPD process while also allowing additional applications to find and localize contamination and possible sources...



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